

# WHEN IS IT AN ATTACK? DISTINGUISHING FAULT INJECTION PERTURBATION FROM ENVIRONMENTAL EFFECTS IN FPGA- BASED DIGITAL SENSOR

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**1.**

**FIA countermeasures context and Digital Sensors introduction**

**2.**

**Calibration**

**3.**

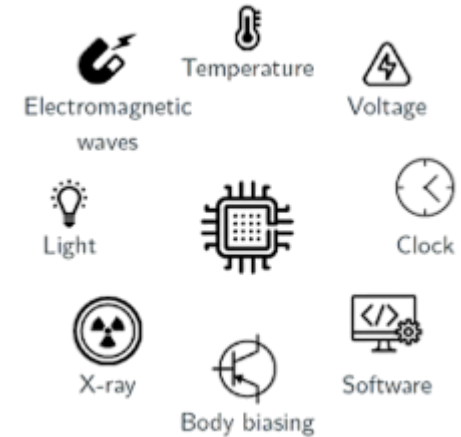
**Outlooks & Conclusion**



# 1. FIA COUNTERMEASURES CONTEXT AND DIGITAL SENSORS INTRODUCTION

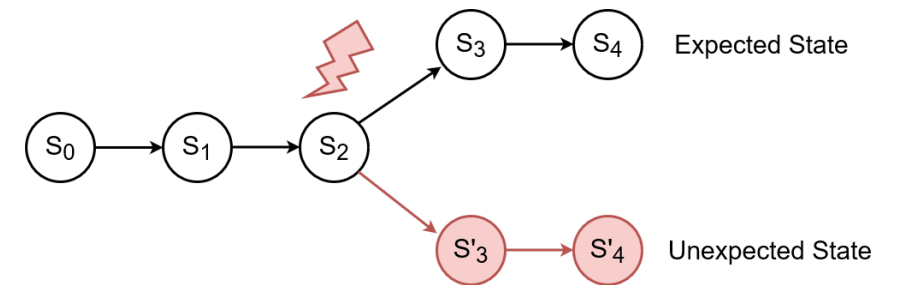
## ■ Goals:

- No unwanted FSM state
- Principle: Detect, Decide and Act
- Metrics: diagnostic coverage, compliance with a target level
  - SIL in IEC 62443
  - ASIL in ISO 26262



## ■ Requirements:

- Fast detection
- Output control
- Bounded response
- Robust design and safe FSM default states



▲ Safety is not Security

# CYBERSECURITY: FIPS 140-3 LEVELS

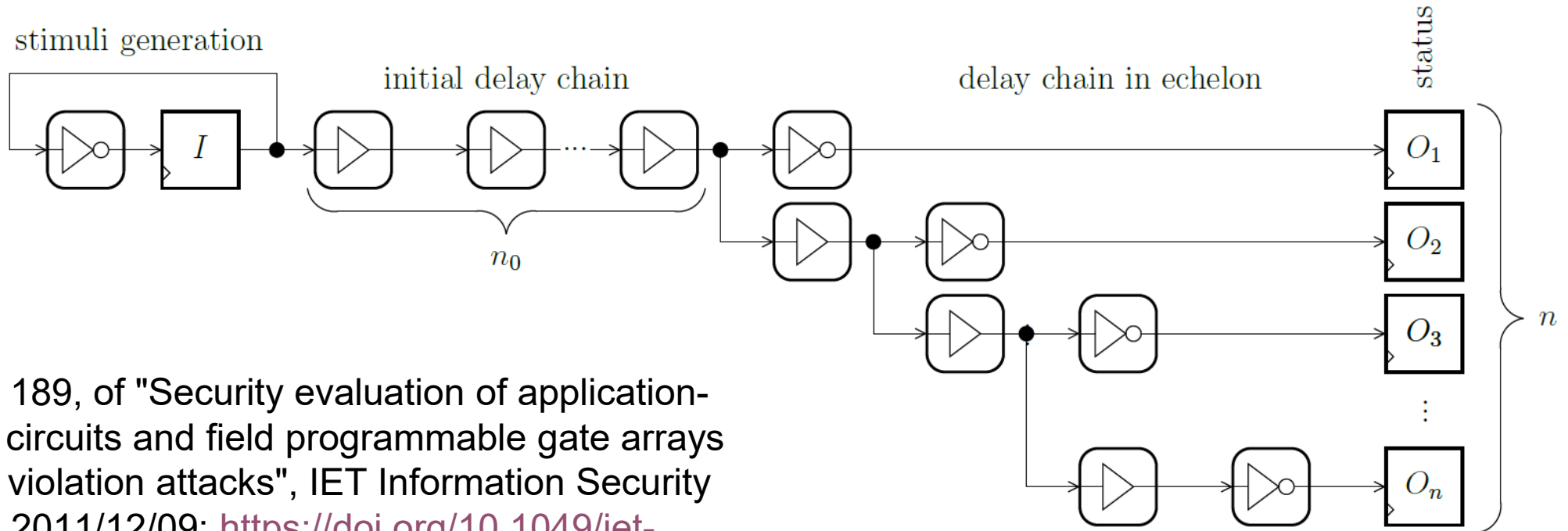
Level	Main Objective	Physical Protection	Key Management	Typical Use Cases
1	Basic security	No special physical requirements	Mandatory cryptographic self-tests	Software libraries, simple crypto modules
2	Tamper-evidence	Tamper-evident coatings, seals, visible protections	Role-based authentication (user/admin)	Smart cards, networking equipment
3	Tamper-resistance	Tamper-resistant enclosure, separation of critical interfaces	Automatic zeroization of keys upon intrusion	Banking HSMs, PKI modules
4	Hostile environment resistance	Active monitoring (voltage, temperature, frequency, radiation, glitching)	Automatic zeroization, protection against fault injection	Military devices, high-security government systems

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- Initial delay chain (length  $n_0$ )
- Delay chain with  $n$  registers
- Output status  $s = (O_1, \dots, O_n)$

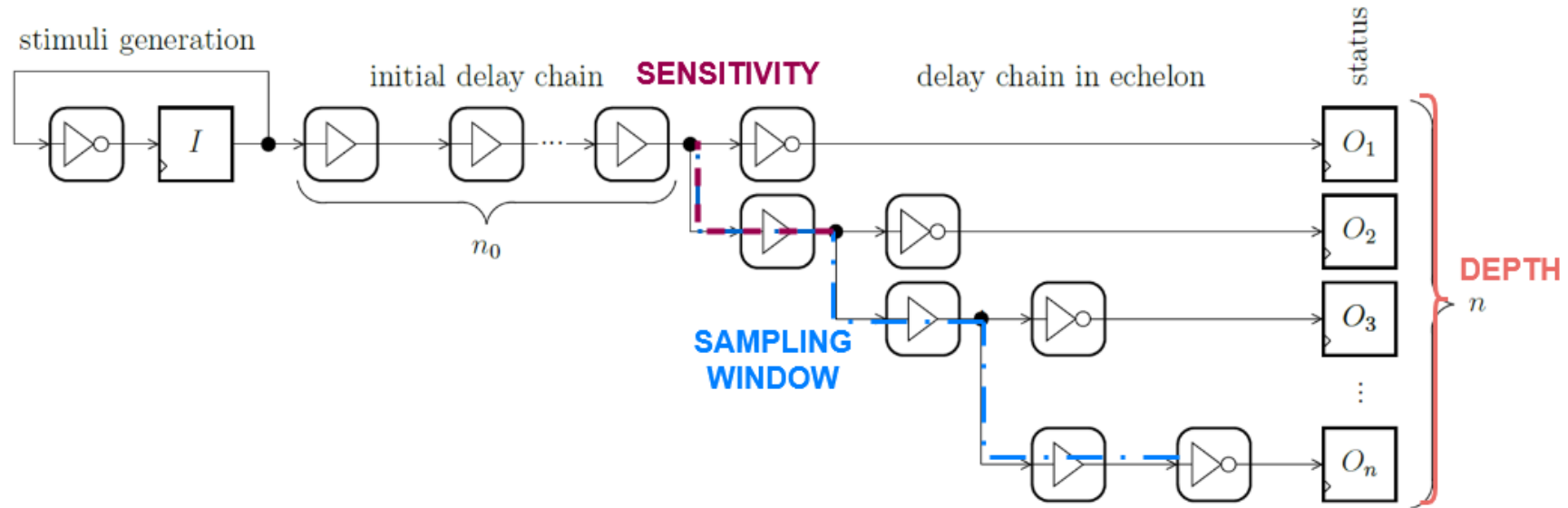
It is a "Time to Digital Converter" (TDC)



See: Fig. 14, page 189, of "Security evaluation of application-specific integrated circuits and field programmable gate arrays against setup time violation attacks", IET Information Security **5**(4), pp. 181~190, 2011/12/09: <https://doi.org/10.1049/iet-ifs.2010.0238>

## 2. CALIBRATION





- Sensitivity  $s$ : number of buffers between two following registers
- Sampling Window  $W$ : « distance » between the first and the last register
- Depth: Number of registers  $n$
- $W = s \cdot n$

## ■ Trimming procedure:

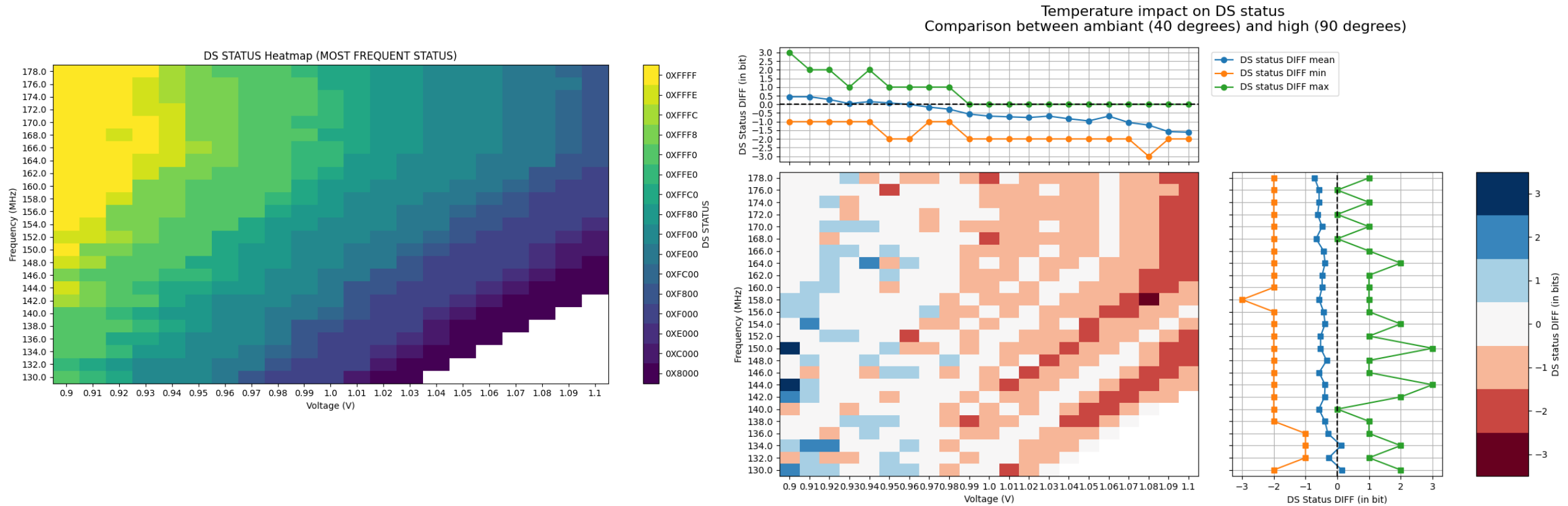
- Objective:
  - Compensate calibration uncertainty
    - Process design kit characterization not fully performed (by the foundry)
    - Gap between simulation and reality (models vs reality, simulation accuracy, RC parasitics)
- Measure propagation delay in delay chains for PVT corner
- Get extremal delay chain status
- Apply mask as alarm threshold

## ■ Normal Operation:

- If delay chain status passes over the threshold, the chain trigs an alarm
- This alarm is sent to the Anti Tamper Unit (an IP that interprets and executes security policy)
- Countermeasures are applied based on the security policy

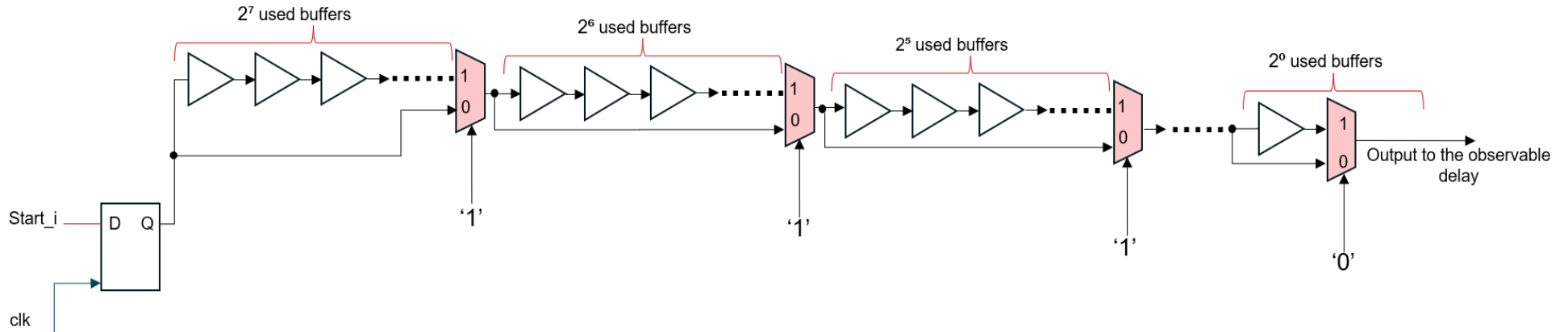


- Propagation delay is strongly influenced by the environmental PVT conditions.  
... and noise is less of an issue



(NEW) objectives:

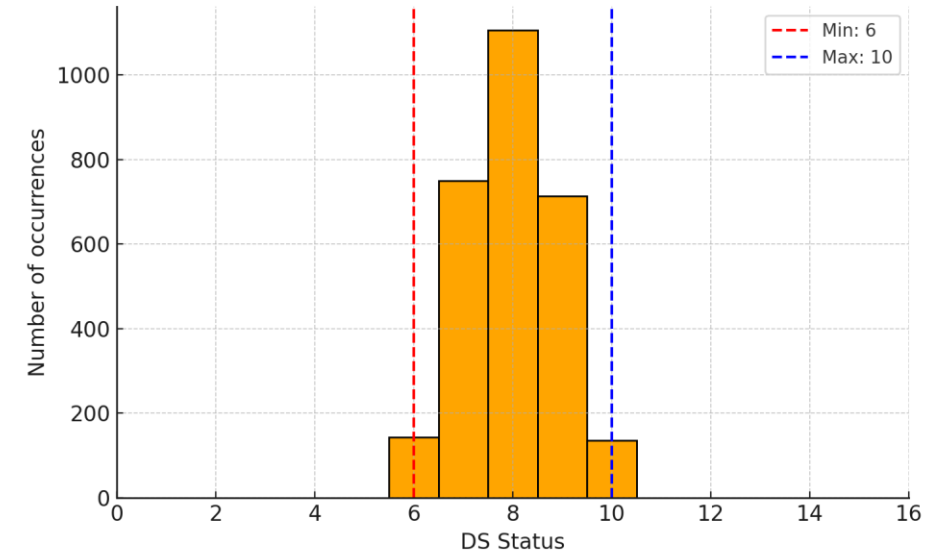
- Change of operational conditions (in the middle of project, in the middle of operations)
  - Inaccuracy of models/simulations/etc..
  - Process design kit not fully characterized (updates requiring recalibration)
- New Initial delay chain with dynamic configuration.



■ Goals:

- Resize the initial delay chain
- Precisely control where the signal stops
- Correct any errors in simulations, noise, or processes

- Objectives:
  - Calibrate based on a reference conditions, not based on worst (worst corner)
  - Adapt sensitivity of sensor, dynamically adapt the security policy.
- Delay chain status varies with PVT conditions
- We now set 2 thresholds:
  - First one under the minimal status value
  - Second one over the maximal status value
- This allows to detect any PVT variations which bypass the nominal functional interval



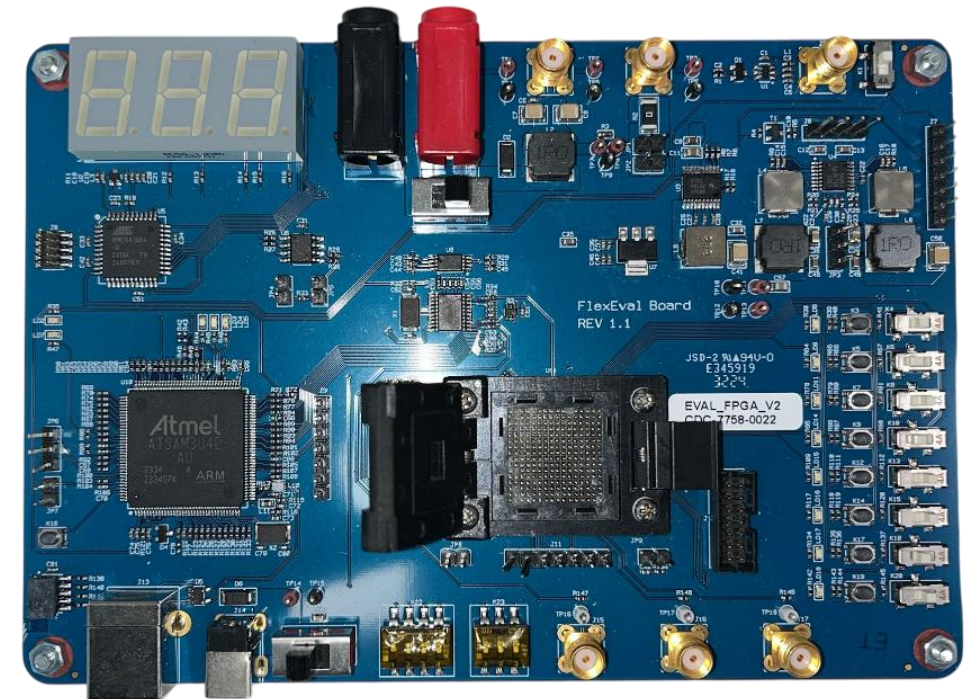
## 3. OUTLOOKS & CONCLUSION

- Confusion matrix

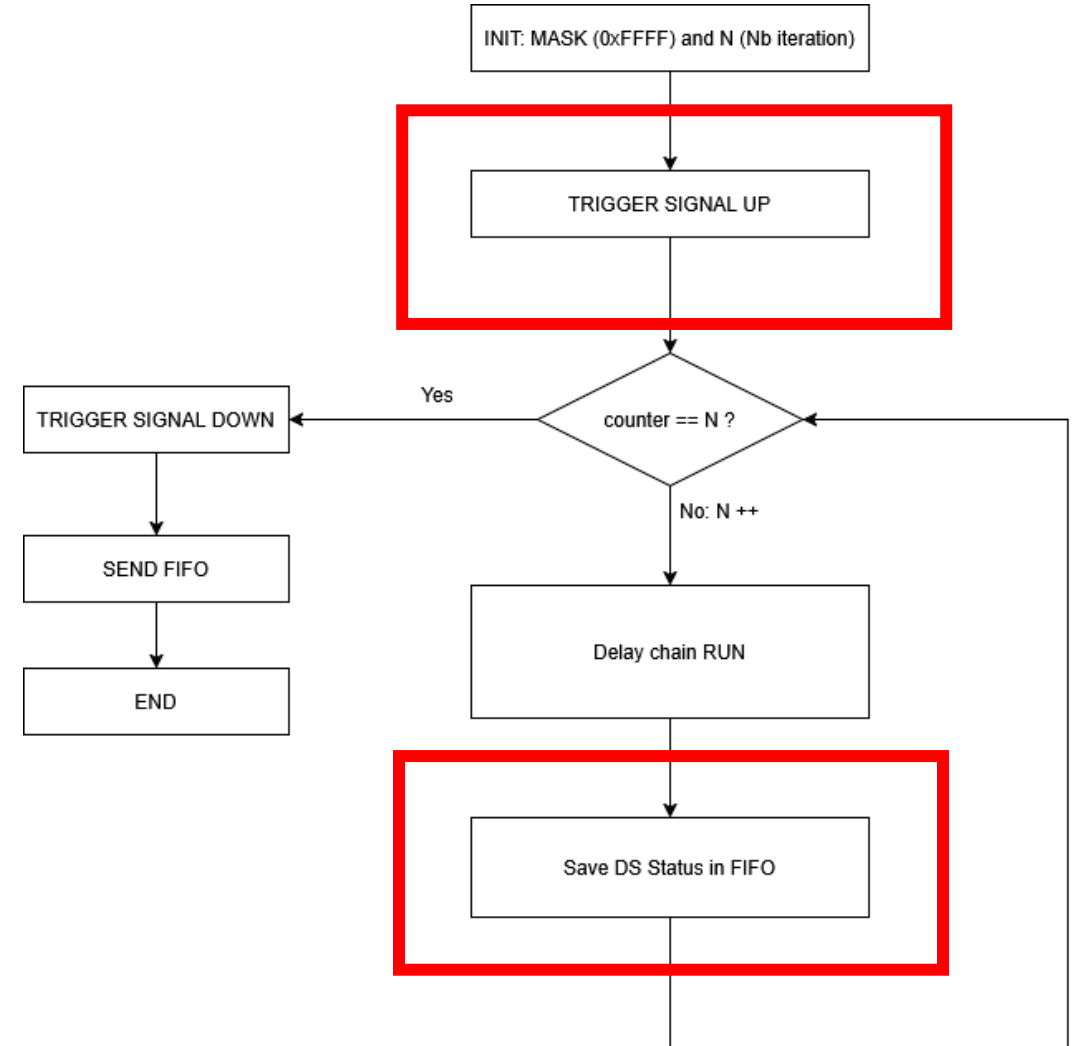
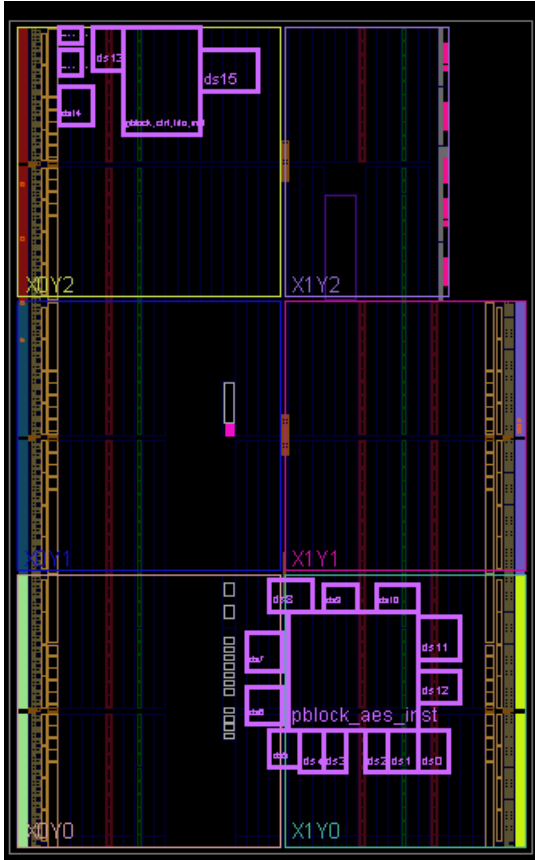
	Attack	No Attack
Alarm	True Positive (TP)	False Positive (FP)
No Alarm	False Negative (FN)	True Negative (TN)

- Goals: Maximise TP and TN (depending on the policy)
- Compliancy to FIPS 140-3 level 4: maximal protection against “environmental attacks”

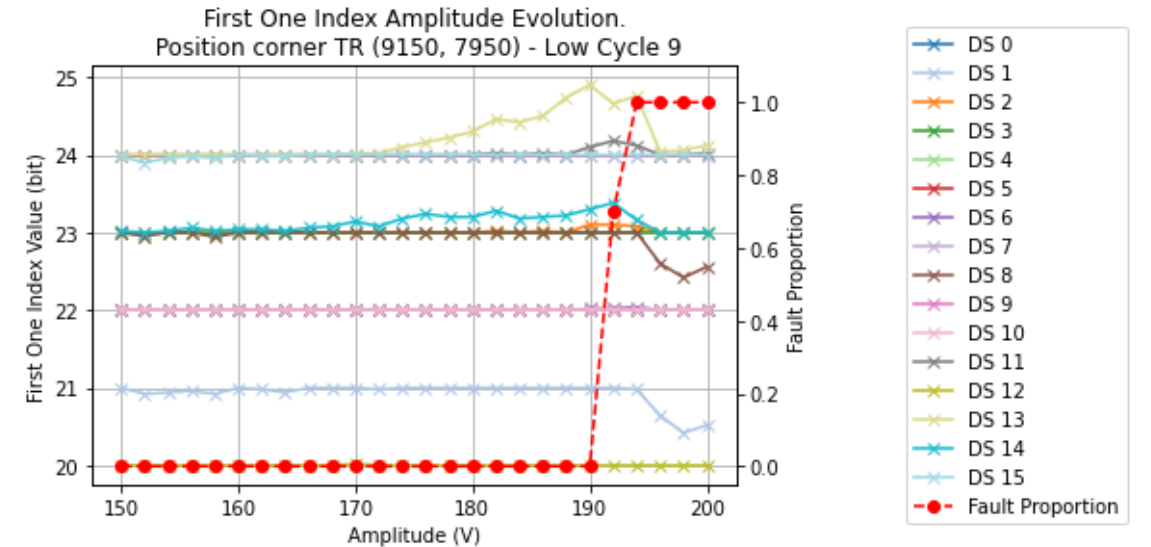
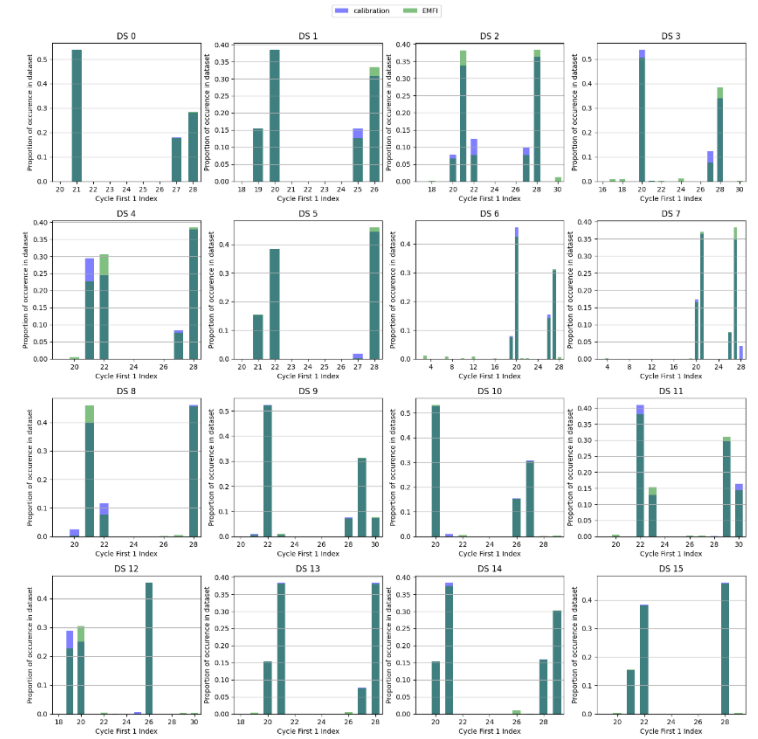
- Based on NewAE CW305 (photo)
- AMD Xilinx Artix 7 series
- MCU Atmel SAM series
- Designed for fault injection, side channel and PVT experimentations.
  - Compatible with specific Peltier (thermoelectric) module
  - Monitoring of FPGA operating figures (T, V)







- Fault injections campaigns (power glitch, clock glitch and EM fault injections)
- Compare delay chain measurements obtained under varying PVT conditions with the measurements during fault injections



# THANK YOU FOR YOUR ATTENTION

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